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Direct synthesis and in situ characterization of monolayer parallelogrammic rhenium diselenide on gold foil

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Rhenium diselenide (ReSe₂) has recently garnered great research interest due to its distorted 1T structure, anisotropic physical properties, and applications in polarization-sensitive photodetectors. However, ReSe₂ synthesized by chemical vapor deposition (CVD) is usually a multilayer/polycrystalline material containing numerous grain boundaries, thereby hindering its further applications. Here we describe the direct CVD growth of high-quality monolayer ReSe₂ single crystals with a parallelogram shape arising from its anisotropic structure on a gold foil substrate. In particular, we use low-energy electron microscopy/diffraction combined with scanning tunneling microscopy/spectroscopy to determine the atomic-scale structure, domain orientation/boundaries, and band features of monolayer ReSe₂ flakes grown directly on gold foils. This work may open new opportunities for the direct synthesis and in situ characterization of CVD-grown monolayer ReSe₂.

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Inspired by graphene research^{1–3}, researchers in science and technology have recently shown increasing interest in two-dimensional (2D) monolayer transition metal dichalcogenides (TMDs, e.g., MoS₂ and WS₂) due to their rich physical, chemical, and electronic properties associated with the dimensionality effect^{4–10}. Rhenium dichalcogenides (ReX₂, X = S or Se) are an emerging class of TMDs which, unlike high-symmetry hexagonal TMDs, crystallize in a distorted CdCl₂ structure with a triclinic symmetry due to charge decoupling from an additional valence electron in each Re atom^{11, 12}. The distortion of the crystal structure affords weak interlayer coupling^{13–15}, making bulk ReX₂ behave as electronically and vibrationally decoupled monolayers. Accordingly, the transition from indirect to direct band gap is not observed in three-atom-thick ReX₂, which is in sharp contrast with hexagonal semiconducting TMDs. More intriguingly, ReX₂ exhibits a low-symmetry crystal lattice owing to its distorted structure, and the resulting anisotropic electrical and optical properties^{16–20} enable applications in polarization-sensitive photodetectors and integrated polarization controllers (such as wave plates)^{21–23}.

Driven by such intriguing properties, researchers have devoted substantial efforts to synthesize monolayer or few-layer ReSe₂ through various routes, including mechanical exfoliation^{12, 19, 20} and chemical vapor deposition (CVD)^{22, 24, 25}. Notably, adhesive tape-based mechanical exfoliation yielded high-quality ReSe₂ flakes from bulk crystals but suffered from unsatisfactory control of the domain size and thickness^{12, 19, 20}. The facile CVD technique was then utilized to fabricate ReSe₂ flakes on diverse dielectric substrates, rendering ReSe₂ flakes with obvious thickness variations and polycrystalline domains^{22, 24, 25}. Additionally, the current characterization routes for recognizing the grain boundaries (GBs) of polycrystalline ReSe₂ are still limited to Raman spectroscopy or ex situ transmission electron microscopy (TEM)^{24, 26}. Additional facile, high-throughput, and in situ identification routes that can evaluate materials from the atomic scale to the domain scale and can effectively achieve characterization of their morphological and electronic properties are still missing despite their importance for guiding the synthesis of samples with controlled orientations and properties.

A system for ReSe₂ growth on a conductive substrate, which is distinct from its growth on insulating substrates, should hold fundamental promise considering its compatibility with powerful characterization techniques such as low-energy electron microscopy/diffraction (LEEM/LEED) and scanning tunneling microscopy/spectroscopy (STM/STS). Multi-scale structural details, as well as electronic properties, can be determined to provide insights into related systems^{27, 28}. Coincidentally, a surface self-limited growth mechanism has recently been proposed by our group and other researchers for achieving high-quality monolayer MX₂ (M: Mo, W; X: S, Se) on a unique Au foil substrate due to the low solubility of Mo, W, S and Se in Au^{29–32}. The extremely low solubility (nearly 0.1 at.% at 1000 °C) of Re in Au³³ may therefore be exploited to develop a new ReSe₂/Au growth system.

Herein, we demonstrate direct synthesis of high-quality monolayer ReSe₂ single crystals on a gold foil substrate via an ambient-pressure CVD (APCVD) route based on a surface self-limited growth mechanism. Using Raman spectroscopy, TEM, and LEEM/LEED, we correlate the lattice orientation and crystallinity with the specific domain shape, thereby establishing a common rule for identifying the single-crystal domain of the structurally anisotropic ReSe₂ (e.g., to determine whether the parallelogram-shaped ReSe₂ domain is monocrystalline). By virtue of high-resolution STM/STS, we also uncover the atomic-scale structures, defects (mainly GBs), and energy band feature of our high-quality monolayer ReSe₂ on Au foils, none of which have been addressed to date, especially regarding CVD-grown ReSe₂ samples.

Results

APCVD synthesis and TEM characterization of monolayer ReSe₂. The growth process of ReSe₂ on the Au foil substrate is schematically displayed in Fig. 1a. Details on the growth methodology and experimental setup are provided in the Methods section and Supplementary Fig. 1, respectively. In brief, the ReO₃ powder precursor (downstream) partially decomposes into highly volatile Re₂O₇ via a disproportionation reaction, and this product is subsequently transported by the Ar and H₂ carrier gases and reacted with the Se precursor (upstream) to form ReSe₂ flakes/films on the Au substrate. In this process, the Au surface is very inert towards the Se precursor, and surface reactions other than that involved in the ReSe₂ synthesis should not occur.

X-ray photoelectron spectroscopy (XPS) was first employed to identify the formation of ReSe₂ on Au foils. Five elements were observed in the full-range XPS spectrum (Supplementary Fig. 2). As also representatively shown in Fig. 1b, the Se 3d spectrum consists of two peaks located at binding energies of 55.8 and 54.9 eV, which correspond to Se 3d_{3/2} and Se 3d_{5/2}, respectively, and the Re 4f spectrum possesses two peaks located at 44.2 and 41.8 eV, which are consistent with Re 4f_{5/2} and Re 4f_{7/2}, respectively. The peak at 57.7 eV is attributed to Au 5p_{3/2}, which arises from the Au substrate. The shifts to lower binding energies for Se 3d and Re 4f relative to those previously reported (Se 3d_{3/2}: 56.0 eV; Se 3d_{5/2}: 55.1 eV; Re 4f_{5/2}: 44.4 eV; Re 4f_{7/2}: 42.0 eV) for monolayer ReSe₂ on SiO₂/Si²⁵ should result from the relatively strong electronic interaction of ReSe₂/Au. In short, the XPS data provide tentative evidence for the evolution of ReSe₂ on Au foils.

Scanning electron microscopy (SEM) images of the as-grown ReSe₂ flakes on Au foils were then obtained, as shown in Fig. 1c,d and Supplementary Fig. 3. Uniform parallelogrammic shapes with a specific angle of ~119° are noticeable between the long and short edges, which is almost equal to the angle (118.91°) between the *a*-axis and *b*-axis of the ReSe₂ crystal²². Moreover, the well-defined parallelogrammic shape can be preserved under different growth time (from 15 to 30 min), but with the long-edge lengths varying from ~2 to ~20 μm, as shown in Fig. 1c,d. In this regard, relatively good crystallinity and unique lattice orientation can be expected for such parallelogram-shaped flakes. More intriguingly, the ratio of the long/short edge length for the parallelogram-shaped ReSe₂ can reach 5.5:1 (Fig. 1d), strongly suggesting anisotropic growth along different lattice orientations. Most of the ReSe₂ domains displayed in Fig. 1c appear to have similar edge directions to each other, which is probably mediated by the steps of the crystalline facets of Au (mainly Au(100)²⁸), i.e., the ReSe₂ domains are aligned with one of their edges along the steps of the Au facets. More generally, the ReSe₂ domains grown on a single Au domain/facet possess different orientations, as shown by the SEM image and its statistical analysis in Supplementary Fig. 3a, b. The lack of strict correlation between the crystal orientation of the ReSe₂ domain and the underlying Au implies that there is no definite epitaxial relationship between the two. This phenomenon was also observed for monolayer MoS₂ synthesized on Au foils²⁹.

The transfer of APCVD-synthesized ReSe₂ from Au foils to SiO₂/Si substrates or TEM grids is highly important for further flake thickness and crystal structure characterization. In this study, a previously developed electrochemical bubbling method³⁰ was exploited to transfer the as-grown sample because of its environmental friendliness. Atomic force microscope (AFM) images of ReSe₂ flakes transferred onto SiO₂/Si are presented in Fig. 1e and Supplementary Fig. 4, showing good maintenance of the initial parallelogrammic shape. The apparent flake height was measured as ~0.9 nm (inset of Fig. 1e), highly indicative of its monolayer nature according to previously published data¹². More AFM data are supplied in Supplementary Fig. 4.

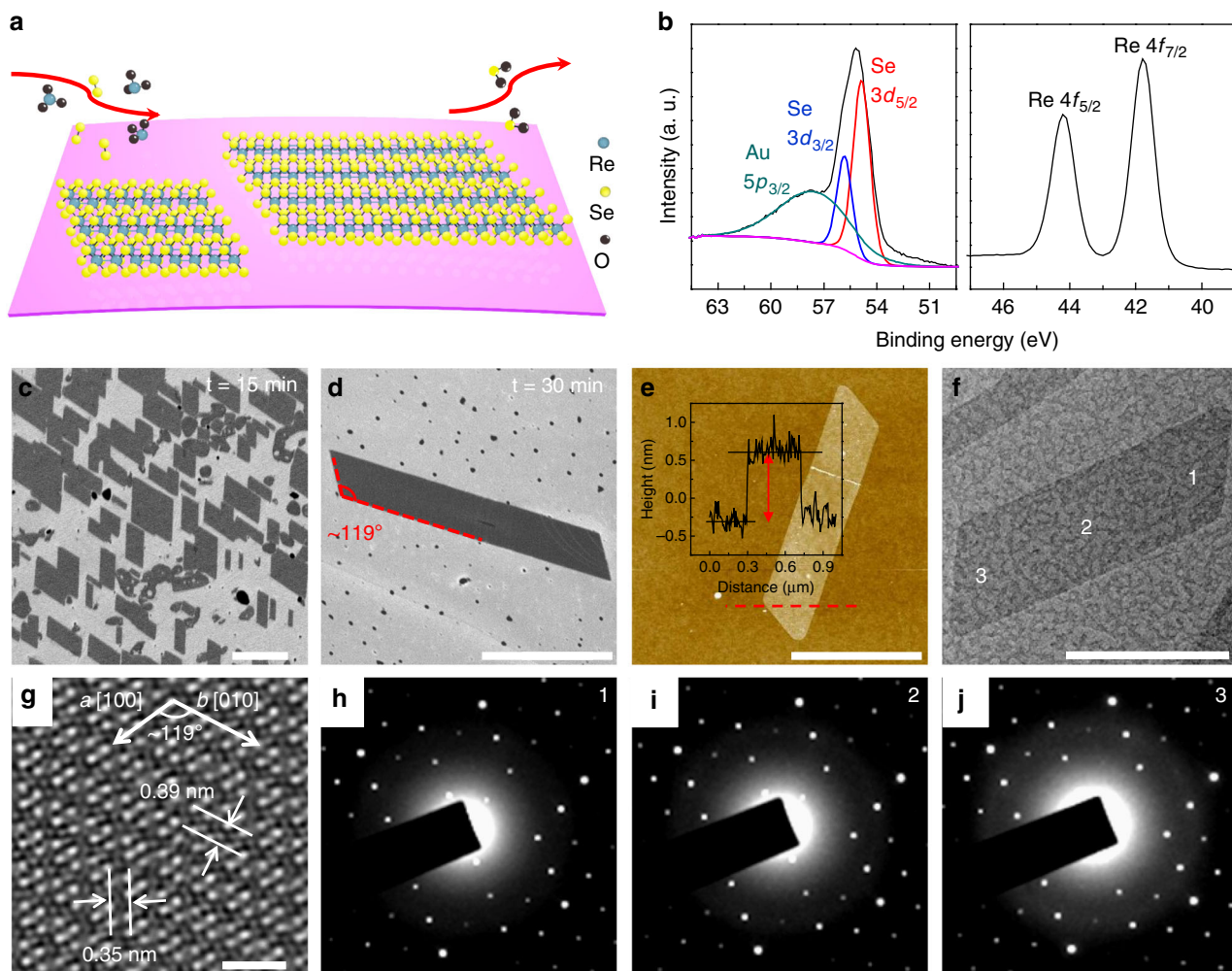


Fig. 1 APCVD synthesis and characterization of monolayer ReSe₂ flakes. **a** Schematic diagram of the surface-mediated growth of ReSe₂ on the Au foil. **b** XPS spectra showing Se 3d and Re 4f peaks in an as-grown sample, confirming the formation of ReSe₂. **c, d** Typical SEM images of the parallelogram-shaped ReSe₂ achieved at different growth times: **c** 15 min and **d** 30 min (under 50 sccm Ar and 10 sccm H₂). **e** Representative AFM image of a ReSe₂ flake transferred onto SiO₂/Si showing a representative monolayer thickness of ~0.9 nm (red arrow). **f** TEM image of a parallelogram-shaped ReSe₂ flake transferred onto a TEM grid. **g** Characteristic STEM image presenting the perfect atomic lattice. **h–j** Three typical SAED patterns collected from the areas labeled 1–3 in **f** revealing nearly identical lattice orientations over the whole flake. Scale bars, 2 μm in **c**, 5 μm in **d**, 1 μm in **e**, 500 nm in **f** and 1 nm in **g**

To clarify the detailed structure, TEM and spherical-aberration-corrected scanning transmission electron microscopy (STEM) analyses were also performed for a parallelogram-shaped ReSe₂ flake transferred onto a copper TEM grid, as shown in Fig. 1f. A representative TEM image of the folded ReSe₂ flake edge revealed a width of ~0.69 nm for the bright line, further indicating its monolayer feature (Supplementary Fig. 5). Specifically, monolayer ReSe₂ crystallizes in a stably distorted 1T structure with a diamond-shaped Re₄ chain along the *b*[010] direction, as shown from the high-resolution STEM image in Fig. 1g. The angle measured between the *b*[010] and *a*[100] axes was ~119°, and the lattice spacing between the two vicinal diamond-shaped chains in the respective directions were ~0.39 and ~0.35 nm, agreeing well with those of the exfoliated sample²⁶. Selected-area electron diffraction (SAED) patterns of three typical locations of a transferred flake (marked 1 to 3 in Fig. 1f) were also collected to show the same crystallographic orientation (Fig. 1h–j).

The above characterization results indicate that the monolayer ReSe₂ flakes universally observed with an ideal parallelogrammic shape should be single-crystalline domains. The monolayer

thickness can be maintained until the complete coverage of the substrate by the ReSe₂ film by extending the growth time to 60 min (Supplementary Fig. 3e). Similar to the mechanisms of monolayer graphene growth on Cu foils³⁴ and of monolayer MoS₂ or WS₂ growth on Au foils^{29–31}, a self-limited catalytic growth mechanism is thus proposed for ReSe₂/Au foils for the following reasons: (1) the Au substrate is more catalytically active for the synthesis of high-quality ReSe₂ than the inert insulating substrates, and (2) the solubility of Re in Au is extremely low (nearly 0.1 at.% at 1000 °C), which allows the surface-catalyzed growth of ReSe₂ with a monolayer thickness.

Optical properties of single-crystal monolayer ReSe₂ domains.

Figure 2a shows representative Raman spectra obtained using a 532 nm laser for as-grown ReSe₂ flakes on Au foils and transferred on SiO₂/Si. More than 10 distinctive Raman peaks are visible in the range of 100–300 cm⁻¹ owing to the low crystal symmetry of ReSe₂. For the as-grown ReSe₂ flake on Au foils, two obvious Raman peaks at ~122 and ~158 cm⁻¹ were detected and assigned to E_g-like and A_g-like vibrational modes, respectively. Notably, the two peaks were redshifted by ~2 cm⁻¹ compared

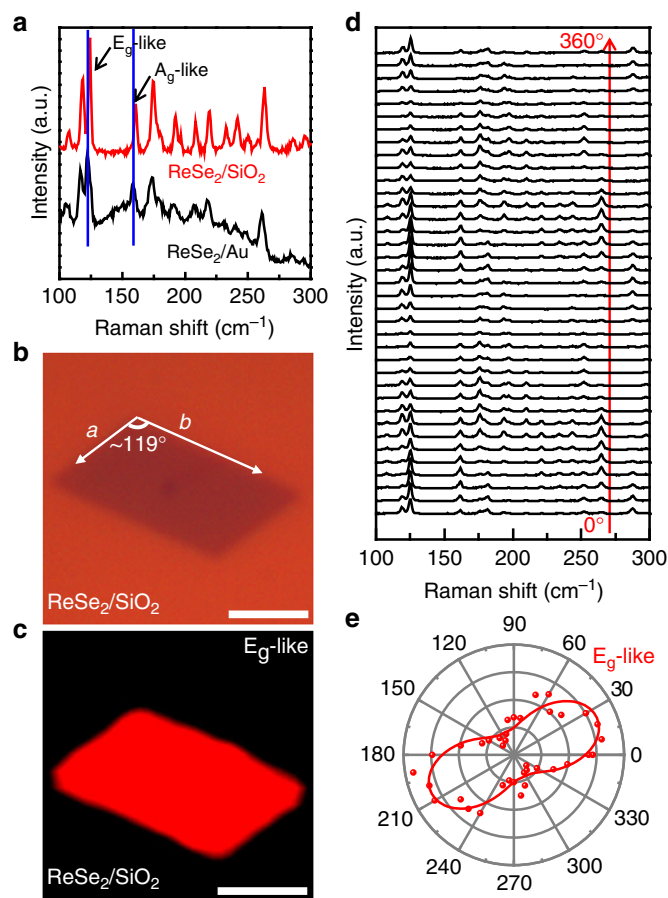


Fig. 2 Optical properties of parallelogram-shaped monolayer ReSe_2 single crystals transferred onto a SiO_2/Si substrate. **a** Comparison of the Raman spectra of as-grown ReSe_2 on Au foils and transferred on SiO_2/Si . **b, c** Optical image and corresponding Raman intensity mapping image of the E_g -like peak of a typical ReSe_2 polygon. **d** Angle-dependent polarized Raman spectra of the ReSe_2 flake transferred onto SiO_2/Si under the parallel polarization configuration with a 514 nm laser for excitation. **e** Polar plot of the Raman E_g -like peak intensities with different sample rotation angles. Scale bars, 2 μm in **b, c**

with those (E_g -like and A_g -like vibrational modes at ~ 124 and $\sim 160 \text{ cm}^{-1}$, respectively) observed after transfer onto SiO_2/Si and with previous results for CVD-grown ReSe_2 on SiO_2/Si ²². This redshift is attributed to an enhanced adlayer-substrate interaction of ReSe_2/Au according to previous work for MoS_2/Au ^{28, 35}. To confirm the crystal quality of the monolayer ReSe_2 flakes, Raman spectroscopy/mapping measurements were also carried out with a laser wavelength of 532 nm. A representative optical image and corresponding Raman intensity mapping image (the E_g -like vibrational mode) for the parallelogram-shaped ReSe_2 transferred onto SiO_2/Si are presented in Fig. 2b,c. Importantly, the Raman intensity is rather uniform across the whole domain, strongly indicating its rather high thickness homogeneity.

Figure 2d shows a series of polarized Raman spectra of the parallelogram-shaped ReSe_2 flake transferred onto SiO_2/Si that were collected at different sample rotation angles (from 0° to 360° with an interval of 10°) under the parallel polarization configuration with a 514 nm laser. Notably, the peak intensities of all the Raman modes are strictly dependent on the sample rotation angle, as clearly shown in the polar plot of the E_g -like mode intensity (Fig. 2e). These Raman data are well consistent with previous reports^{22, 24}, thereby confirming the anisotropic nature of the single-crystal domain and denoting the specific edge

orientations in the crystallization process, i.e., the alignments of the a -axis or b -axis along the short or long edges of the parallelogrammic ReSe_2 domain²². Briefly, angle-resolved polarized Raman spectroscopy is suitable for identifying the optical in-plane anisotropy, as well as the crystalline orientation of our transferred monolayer single-crystal ReSe_2 .

LEEM and LEED characterization of monolayer ReSe_2 . Considering the in situ imaging ability and the complementary diffraction function of LEEM^{27, 36–38} and the conductivity of ReSe_2/Au foils, bright-field LEEM (BF-LEEM) was then utilized to image the crystalline structure of the ReSe_2 parallelogram, as shown in Fig. 3a. Corresponding micro-region LEED (μ -LEED) patterns were also collected from representative regions marked 1–3 in Fig. 3a (selected regions of $2 \mu\text{m}$ in diameter). Nearly identical lattice orientations can be observed in Fig. 3b, accordingly indicating the single-crystal feature of the monolayer parallelogram-shaped ReSe_2 domains, in good agreement with the TEM and SAED results in Fig. 1. Additional LEEM/LEED characterization of the crystalline structure of the ReSe_2 parallelogram is described in Supplementary Fig. 6.

For more evidence, representative BF-LEEM and corresponding LEED characterization of three discrete ReSe_2 parallelograms was also performed (Supplementary Fig. 7a). Interestingly, the dark-field LEEM (DF-LEEM) image shown in Supplementary Fig. 7b reveals that the parallelogram-shaped ReSe_2 flakes with parallel edges usually possess the same contrast and therefore have the same lattice orientation. Furthermore, BF-LEEM characterization of three merged ReSe_2 parallelograms was also carried out (Fig. 3c). Corresponding LEED patterns recorded from the three domains (denoted 4–6 in Fig. 3c) display three sets of patterns possessing different orientations (Fig. 3d), thereby indicating their different lattice orientations. Surprisingly, the orientations of the LEED patterns are firmly related to the directions of the short edges of each ReSe_2 parallelogram (see Fig. 3c, d), being positioned at approximately 11° , 142° , and 129° with regard to the horizontal direction. Further DF-LEEM image (Fig. 3e) exhibits clearly different contrasts among the three domains, and their merging boundaries are also clearly visible. Additional LEEM/LEED characterization of the orientation/boundary of the polygonal ReSe_2 domains is described in Supplementary Fig. 7c, d. It is worthy of mentioning that this domain orientation/boundary imaging method of LEEM/LEED is distinguished from the commonly used dark-field TEM method, which usually involves a sample transfer process^{39–41}. DF-LEEM accompanied with μ -LEED techniques is thus promising for serving as an in situ, nondestructive, and high-throughput method for determining the crystal structure of anisotropic 2D monolayer ReSe_2 grown on conductive substrates. In addition, this identification method is also applicable to other 2D-layered materials synthesized on various conductive substrates.

Atomic and electronic structures of monolayer ReSe_2 . The CVD-grown monolayer ReSe_2 on Au foil was also directly analyzed by high-resolution STM/STS to uncover its atomic-scale morphology and electronic properties in an as-grown state. Prior to the STM measurements, the CVD-grown ReSe_2/Au was degassed overnight at $\sim 400^\circ\text{C}$ in an ultrahigh-vacuum chamber to remove adsorbed impurities. Figure 4a shows a large-scale STM image of the sample surface, in which a large-area monolayer ReSe_2 film is observed to extend over the flat Au terraces. The corresponding atomically resolved STM image (Fig. 4b) reveals perfect quasi-hexagonal surface lattices, indicating the relatively high crystal quality of the CVD-grown ReSe_2 flakes. The unit cell, which is composed of the brightest neighboring spots,

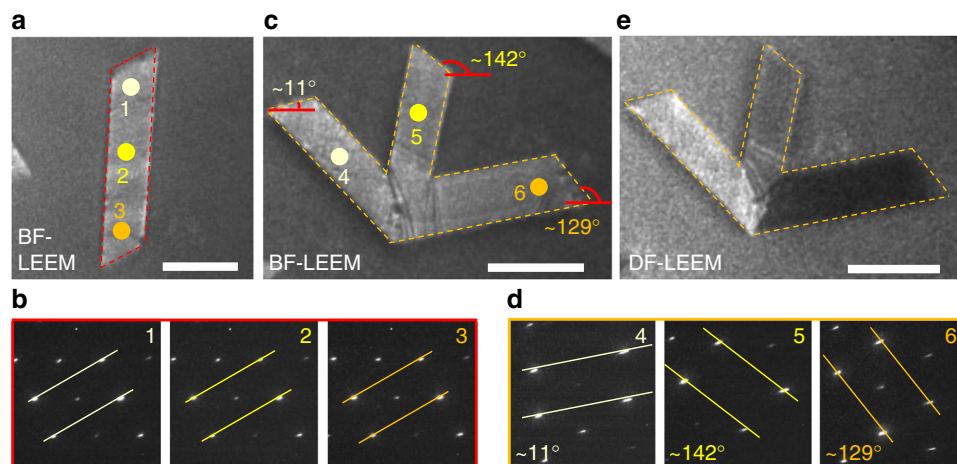


Fig. 3 In situ LEEM and μ -LEED characterization of the orientations and boundaries of monolayer ReSe_2 domains on Au foils. **a** LEEM image (at 7.3 eV) of a monolayer ReSe_2 parallelogram on Au foil. **b** LEED patterns (at 50 eV) from the regions marked 1–3 in **a** reconfirming the single-crystal nature of the sample. **c** BF-LEEM image (at 1.5 eV) of three merged ReSe_2 domains. **d** LEED patterns (at 50 eV) recorded from the domains denoted 4–6 in **c**. The angles of the marked solid lines with respect to the horizontal direction are labeled in the patterns. **e** DF-LEEM image (at 9.8 eV) from the same area in image (**c**) showing remarkably different contrasts for the three merged parallelograms. Scale bars, 5 μm in **a**, **c**, **e**

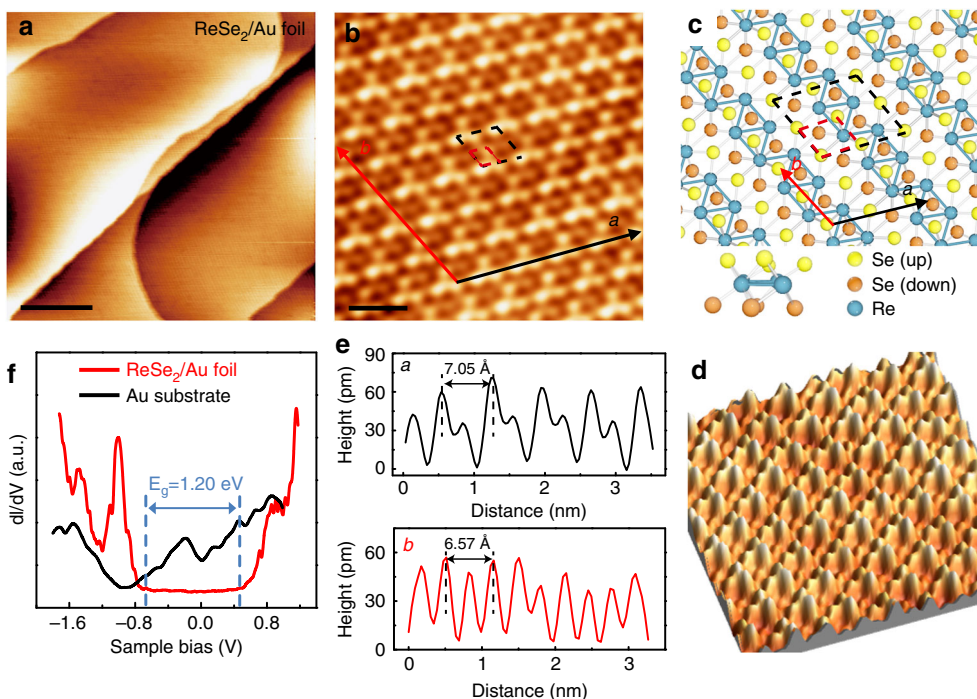


Fig. 4 Atomic structure and electronic properties of monolayer ReSe_2 on Au foils. **a** Large-scale STM image ($V_T = -0.05$ V, $I_T = 12.64$ nA; $215 \text{ nm} \times 215 \text{ nm}$) of as-grown monolayer ReSe_2 on a Au foil substrate. **b** Atomically resolved STM image (-0.003 V, 12.64 nA; $5.3 \text{ nm} \times 5.3 \text{ nm}$) revealing the perfect atomic lattice of CVD-grown ReSe_2 . The unit cell and the top four non-identical Se atoms of ReSe_2 are marked by black and red dashed parallelograms, respectively. **c** Top and side views of the structural model of ReSe_2 . The a -axis and b -axis, unit cell and top four Se atoms are denoted by black and red arrows, a black dashed parallelogram and a red dashed parallelogram, respectively. **d** Corresponding 3D STM image of the ReSe_2 lattice showing an undulating surface. **e** Height profiles along the two typical lattice orientations (a -axis and b -axis) revealing different lattice constants of ~ 7.05 Å and ~ 6.57 Å, respectively. **f** Typical STS spectra (1.50 V, 210 pA, $V_{\text{rms}} = 10$ mV, $f = 932$ Hz) taken on monolayer ReSe_2/Au (red) showing a band gap of -1.20 eV and on the Au substrate (black) as a reference. Scale bars, 50 nm in **a** and 1 nm in **b**

and the four adjacent spots, which are characterized by gradually increasing STM contrasts, are indicated by the black and red dashed parallelograms, respectively. According to the atomic model in Fig. 4c, the observed spot-like contrasts (e.g., the four typical spots in the red dashed parallelogram) correspond to the upper Se atoms (e.g., four Se atoms) of ReSe_2 . Additional

sequential zoomed-in STM images are supplied in Supplementary Fig. 8 to show a ReSe_2 film covering terraced Au and the coexistence of atomic lattices and the underlying terraces.

Notably, the STM contrast variations inside each unit cell (indicated by the black dashed parallelogram) can be visually observed in the corresponding 3D STM image (Fig. 4d), which is

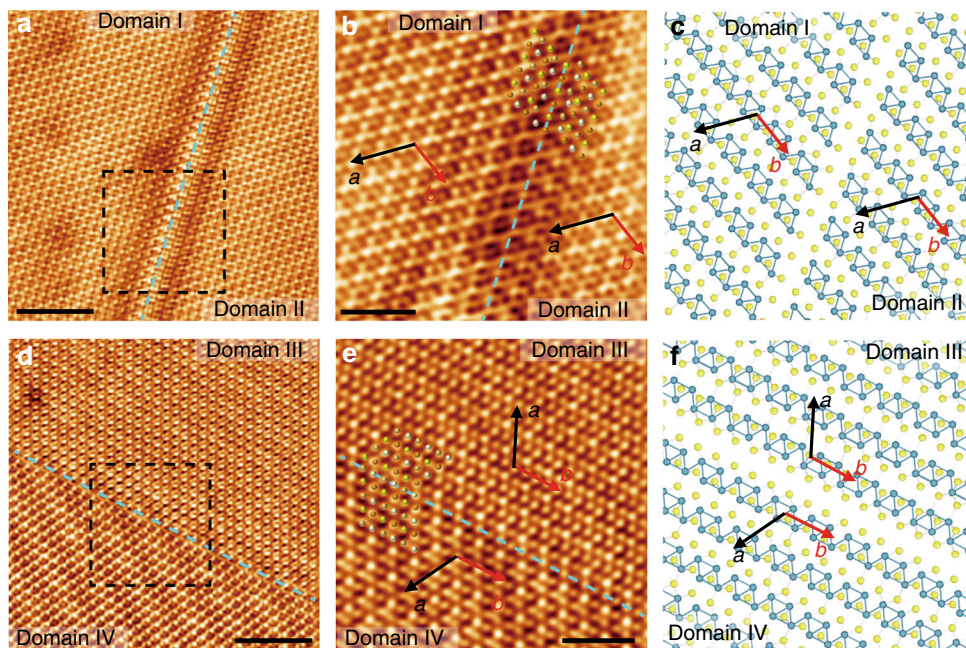


Fig. 5 STM images of two typical GBs in the ReSe₂/Au sample. **a** Large-scale STM image (−0.004 V, 12.64 nA; 20 nm × 20 nm) of a GB composed of a parallel dislocation between two adjacent ReSe₂ domains. **b** Magnified STM image (−0.003 V, 12.64 nA; 8.3 nm × 8.3 nm) of **a** with the fitted atomic models superimposed. The yellow dots with color gradients represent the upper Se atoms with different STM contrasts. The GB and the *a*-axis and *b*-axis of domains I and II are marked by a blue dashed line and black and red arrows, respectively. **c** Corresponding schematic illustration of the evolution of the GB shown in **a**, **b**. Only the upper layer Se atoms are shown here for clarity. The *a*-axis and *b*-axis of the two domains are marked by black and red arrows, respectively. **d** Large-scale STM image (−0.008 V, 30.77 nA; 20 nm × 20 nm) of a mirror twin GB. **e** Magnified STM image (−0.005 V, 30.77 nA; 8.30 nm × 8.30 nm) of **d** with the fitted atomic models superimposed. **f** Corresponding schematic illustration of the GB shown in **d**, **e**. Scale bars, 5 nm in **a**, **d** and 2 nm in **b**, **e**

in sharp contrast with the honeycomb-like lattices of MoS₂ possessing uniform spot-like contrasts inside each unit cell^{28, 42}. This contrast fluctuation stems from the anisotropic structure of ReSe₂^{12, 43}. Typically, ReSe₂ crystallizes in a distorted 1T structure, and the four typical Re atoms are arranged into a diamond-shaped chain along the *b*-axis direction (along the red arrow in Fig. 4c). This structural distortion breaks the hexagonal symmetry and affords a doubled unit cell size (indicated by the black dashed parallelogram) compared to the configuration of the initial four Se atoms (marked by the red dashed parallelogram). The four Se atoms are not all in the same plane^{12, 43}, which explains the varied contrasts in the STM image⁴⁴.

It has been reported that the two principal crystal axes of ReSe₂, corresponding to the shortest (*b*-axis) and second-shortest axis (*a*-axis) in the basal plane, have an angle of ~118.91°²². Herein, the height profiles taken along these two typical lattice directions (*a*-axis and *b*-axis; marked in Fig. 4b, plotted in Fig. 4e) reveal two lattice constants of 7.05 ± 0.2 and 6.57 ± 0.1 Å, respectively, in line with the previous report⁴⁵. Furthermore, low-temperature (~78 K) STS measurements were also conducted to explore the electronic structure of monolayer ReSe₂/Au foils. As shown in Fig. 4f, the valence band maximum and conduction band minimum of ReSe₂/Au are located at ~−0.70 and +0.50 V, respectively, indicating a slight n-doping effect of monolayer ReSe₂ on Au foils. The quasiparticle band gap (E_g) of ReSe₂/Au (~1.20 eV) is evidently much smaller than the theoretical value (~2.09 eV)⁴³, probably due to the strong interfacial electronic interaction, which introduces metal-induced gap states to ReSe₂ from the Au substrate, as similarly reported for MoS₂ on Au foils with a reduced band gap^{46, 47}. As a side evidence, the STS spectrum of the Au substrate shows an apparent tunneling contribution at a larger bias range than the band gap region of ReSe₂.

Detailed structures of ReSe₂ GBs. Current knowledge of the detailed structure of the GBs of structurally isotropic 2D materials, e.g., graphene and MoS₂, is relatively comprehensive, revealing the existence of 4-membered-ring, 5-membered-ring, 7-membered-ring or 8-membered-ring types of defects^{39, 48–52}. However, for ReX₂, the large anisotropic interfacial energies imposed by their anisotropic structure make the structures of their GBs quite ambiguous, although efforts have been made using ex situ TEM characterization^{26, 53}. In this work, detailed STM studies were first used to address such issues for the CVD-grown monolayer ReSe₂/Au system.

A typical GB with a bright line-shaped contrast (marked by a blue dashed line) was captured between two neighboring domains (Fig. 5a and Supplementary Fig. 9). Since the STM morphology of the two composite domains (marked I and II) are quite similar, identifying the *a*-axis and *b*-axis of each is essential to distinguish their domain orientations. This can be realized by mapping the height profiles along the three different lattice directions (Supplementary Fig. 9) considering the inequivalence of the ReSe₂ lattices^{12, 43}. Consequently, domains I and II are revealed to have nearly the same lattice constants/orientations, and the *a*-axis and *b*-axis of the two domains are marked in Fig. 5b. Notably, in the further zoomed-in STM image in Fig. 5b, the bright line-shaped contrast at the GB almost disappears, and the patching interface becomes much clearer. The upper Se atoms imaged by STM are almost continuous at the GB but with a little distortion (as indicated by the fitted atomic model), which is free of apparent dislocation cores or defects. Accordingly, this patching behavior can be defined as two parallel domains with a dislocation, as also schematically shown in Fig. 5c for a clearer view.

Another typical GB is presented in Fig. 5d and Supplementary Fig. 10, wherein domains III and IV have apparently different

STM contrasts even in the large-scale STM image. A perfect lattice coherence between the two adjacent domains is noticeable in the magnified STM image in Fig. 5e (as indicated by the fitted atomic model). A similar method was also used to identify the orientation of each domain (Supplementary Fig. 10). The results indicate that for domains III and IV, the *b*-axis directions are the same, whereas the *a*-axes are reversed. In this regard, this typical GB can be considered as a mirror twin boundary, as schematically shown in Fig. 5f. To illustrate the atomic bonding feature at the two typical GBs mentioned above, density functional theory (DFT) calculations were also performed, and the results coincide well with the STM observations (Supplementary Fig. 11 and Supplementary Discussion). More STM images of the twist GBs are provided in Supplementary Fig. 12, and the patching interfaces are similarly free of obvious defects.

Previous STEM studies revealed that the GBs in ReX₂ evolved when the orientation of the Re-chain was changed by electron beam irradiation or the vacancy defects around the GBs^{26, 53}. However, this ex situ characterization cannot avoid the artificial destruction induced by the transfer process and the effect of high-energy electron bombardment by TEM analysis. Accordingly, the intrinsic defect type of GBs may not be well resolved. In contrast, the CVD-grown ReSe₂/Au foil synthesized in this work serves as an ideal platform for uncovering the intrinsic structures of GBs using in situ STM/STS characterization. To the best of our knowledge, this is the first report of an STM study on the GBs of ReSe₂. Nevertheless, it is noteworthy that further theoretical and experimental efforts are still desirable for an in-depth understanding of the GBs.

Discussion

In summary, we have accomplished the highly uniform synthesis of high-quality monolayer ReSe₂ single crystals on Au foils using an APCVD method. We then identify the single-crystal nature of the parallelogram-shaped ReSe₂ domains by using various methods, including Raman spectroscopy, TEM, and LEEM/LEED. The novel monolayer growth of ReSe₂ on Au foils is directed by a self-limited catalytic growth mechanism, and the specific parallelogram shape is mainly mediated by its anisotropic structure. Direct growth on Au foil allows the atomic-scale morphology and intrinsic band feature of monolayer ReSe₂ directly on Au foils to be analyzed using in situ STM/STS. We believe that this work should pave the way towards the direct synthesis and in situ characterization of anisotropic 2D-layered materials such as ReSe₂ and propel their fundamental property investigations and practical applications in next-generation electronic and optoelectronic devices.

Methods

Synthesis of ReSe₂. The synthesis of single-crystalline monolayer ReSe₂ on Au foils was conducted in a multi-temperature-zone APCVD tube furnace equipped with a quartz tube (1 inch in diameter). Before growth, the Au foil (ZhongNuo Advanced Material Technology Co., Ltd., 30 μm thick, 99.99% purity) was annealed at 970 °C for 8 h to reduce its surface roughness. Five milligrams ReO₃ powder (Alfa Aesar, 99.9% purity) and 1 g Se powder (Alfa Aesar, 99 + % purity) were utilized as the Re and Se precursors for the CVD growth. The Au substrate with an area of 1 cm × 1 cm was placed in a quartz boat at the center of the furnace. To expel air, the tube furnace was first flushed with ultra-high-purity Ar gas. The furnace was then heated to 750 °C over 30 min and maintained at 750 °C for 15, 30, or 60 min for growth under a constant flow rate of Ar gas of 50 sccm and H₂ gas of 10 sccm at atmospheric pressure. After the synthetic procedure, the furnace was naturally cooled to room temperature.

Transfer of ReSe₂. For sample transfer, the ReSe₂/Au samples were first spin-coated with poly(methyl methacrylate) (PMMA) at 2500 rpm for 1 min, resulting in a uniform polymer film on the sample surfaces, and then were baked at 120 °C for 15 min. Next, the PMMA film, together with ReSe₂ flakes, was detached from the Au substrate using an electrochemical bubbling method³⁰. PMMA-supported ReSe₂ was then washed with deionized water several times, transferred onto

SiO₂(300 nm)/Si substrates or TEM grids, and dried on a hot plate at 80 °C. Finally, the PMMA was removed using acetone and isopropanol.

Characterization of ReSe₂. The synthesized ReSe₂ flakes were systematically characterized using SEM (Hitachi S-4800, 2 kV), AFM (Bruker Dimension Icon), Raman spectroscopy (HORIBA iHR550, excitation light wavelengths of 514 and 532 nm), XPS (Kratos Analytical AXIS-Ultra with monochromatic Al Kα X-ray), TEM (FEI Tecnai F20, acceleration voltage of 200 kV), STEM (JEOL JEM-ARM200CF, acceleration voltage of 200 kV), and LEEM/μ-LEED (Elmitec LEEM-III system with ultrahigh vacuum of ~1 × 10⁻¹⁰ Torr). Ultrahigh-vacuum low-temperature STM/STS systems were also utilized for the atomic-scale structural characterization under a base pressure of better than 10⁻¹⁰ mbar. All the STM images were obtained at room temperature. The STS spectra were acquired at ~78 K by recording the output of a lock-in system with the manually disabled feedback loop. A modulation signal of 10 mV at 932 Hz was selected under a tunneling condition of 1.50 V and 210 pA.

DFT calculations. DFT calculations were performed by the Vienna ab initio simulation package using the plane-wave basis set⁵⁴ with an energy cutoff of 450 eV and the projector-augmented wave⁵⁵ potentials and the generalized gradient approximation parameterized by Perdew, Burke and Ernzerhof for the exchange-correlation functional⁵⁶.

Data availability. The data reported by this article are available from the corresponding author upon reasonable request.

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Author contributions

Y.Z. conceived and supervised the research project. S.J. performed CVD growth and transfer of ReSe₂, with Z. Z., P.Y., X. Z., C. X., J.S., and Y.H.'s assistance. M.H. carried out the STM/STS characterization. W.W., and Q.F. performed the LEEM/LEED characterization. S.J., Z.Z., P.Y., X.Z., C.X., J.S., and Y.H. carried out the optical microscopy, XPS, SEM, AFM, TEM, and STEM characterizations. L.Z., N.Z., L.T., and Q.Z. performed Raman spectroscopy characterization. N.G. and J.Z. performed the DFT calculations. S.J., M.H., Q.F., and Y.Z. co-wrote the manuscript and all authors contributed to the critical discussions of the manuscript.


Additional information

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